	Subclass	
Class		ISSUE CLASSIFICATION

PATENT NUMBER

Best Available Copy

U.S. **UTILITY** Patent Application

O.I.P.E.

SCANNED _____ Q.A. _Am_

PATENT DATE

5c 84u

APPLICATION NO.	CONT/PRIOR	CLASS	SUBCLASS	ART UNIT.	EXAMINER	
09/736282	F	714	719	2133	Chase	3
			RSD			

APPLICANTS

Hideyuki Aoki
Takeshi Wada
Masaaki Niura
Noboru Uchida

TITLE

Method of testing memory device, method of manufacturing memory device, apparatus for testing memory device, method of testing memory module, apparatus for testing memory module, method of manufacturing memory module and method of manufacturing computer

PTO-2040
12/99

ISSUING CLASSIFICATION

ORIGINAL			CROSS REFERENCE(S)						
CLASS	**SUBCLASS**	**CLASS**	**SUBCLASS (ONE SUBCLASS PER BLOCK)**						

INTERNATIONAL CLASSIFICATION

☐ Continued on Issue Slip Inside File Jacket

☐ TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
☐ The term of this patent subsequent to _____ (date) has been disclaimed.	(Assistant Examiner) (Date)			NOTICE OF ALLOWANCE MAILED	
☐ The term of this patent shall not extend beyond the expiration date of U.S Patent. No. _____				ISSUE FEE	
				Amount Due	Date Paid
	(Primary Examiner) (Date)			ISSUE BATCH NUMBER	
☐ The terminal ____ months of this patent have been disclaimed.	(Legal Instruments Examiner) (Date)				

WARNING:

The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368. Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.

FILED WITH: ☐ DISK (CRF) ☐ FICHE ☐ CD-ROM
(Attached in pocket on right inside flap)

Form PTO-436A
(Rev. 6/99)

(FACE)